

**Notice of References Cited**

Application/Control No.

10/718,972

Applicant(s)/Patent Under  
Reexamination  
OWN, CHRISTOPHER SU-YAN

Examiner

Howard L. Williams

Art Unit

2819

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0252966 A1	12-2004	Holloway et al.	386/046
*	B	US-5,268,688	12-1993	Meyers et al.	341/143
*	C	US-6,943,459 B2	09-2005	Hartman et al.	290/1C
*	D	US-5,351,048 A	09-1994	Yamasaki, Yoshio	341/110
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Stewart, R.W., An Overview of Sigma Delta ADCs and DAC Devices, Nov. 1995, IEEE, IEE Colloquium on Oversampling and Sigma-Delta Strategies for DSP, pages 1/1-1/9.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.